



**MICROCHIP**

## **QUALIFICATION PLAN SUMMARY**

**PCN #: MAAN-06XMVV963**

**Date:**

**April 24, 2026**

**Qualification of ARDE as an additional final test site for selected A3PE3000, A3PE3000L, M1A3PE3000 and M1A3PE3000L device families available in 896L PBGA (31x31x2.44mm) package.**

**Purpose:** Qualification of ARDE as an additional final test site for selected A3PE3000, A3PE3000L, M1A3PE3000 and M1A3PE3000L device families available in 896L PBGA (31x31x2.44mm) package.

**CCB No.:** 7922

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria
<b>Bin and Yield Comparison</b>	Test the same units at existing and destination locations and compare Bin and Yield data.	30	1	≤0.1%
<b>Parametric / Characterization Comparison</b>	Characterize the same units at existing and destination locations and compare data.	30	1	≤10%
<b>Correlation Lot report</b>	Yield at each step and reject analysis between systems. 30 units are tested as lot correlation <ul style="list-style-type: none"><li>• Accept on yield match within 0.1%</li></ul>	30	1	≤0.1%